Docket No.: MUH 11449

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant

GUNNAR KRAUSE ET AL.

Filed

Concurrently herewith

Title

METHOD AND DEVICE FOR OFFSET-VOLTAGE FREE VOLTAGE MEASUREMENT AND ADJUSTMENT OF A REFERENCE VOLTAGE SOURCE OF AN INTEGRATED

SEMICONDUCTOR CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks, Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

German Patent DE 197 35 381 C1 (Franz Kuttner), dated January 14, 1999, pertains to a band gap constant-voltage source and process for its operation;

U. Tietze et al: "Halbleiter-Schaltungstechnik" (Semiconductor Circuit Engineering), Springer-Verlag, 1969, pages 212-213, and 60-63.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications,



patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,

For Applicants

WERNER H. STEMER REG. NO. 34,956

Date: July 3, 2001

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/vs

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: MUH 11449 Appl. No. Applicant GUNNAR KRAUSE ET AL.				
				Filing Date July 3, 2001 Group Art Unit			Jc821 U.S.	
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		U. Tietze et al: "Halbleiter-Schaltungstechnik" (Semiconductor Circuit Engineering), Springer-Verlag, 1969, pages 212-213, and 60-63						
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